JJMICROELECTRONICS

68V, 80A, 7.3mΩ N-channel Power Trench MOSFET JMTK70N07A

Features

- Excellent $\mathsf{R}_{\mathsf{DS}(\mathsf{ON})}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant
- Pb-free plating

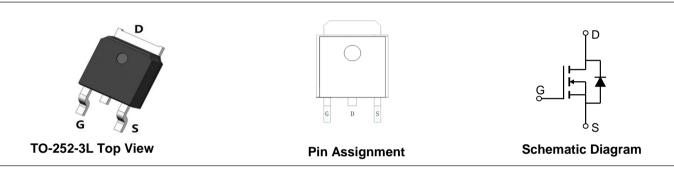
Applications

- Load Switch
- PWM Application
- Power Management

Parameters Value Unit V_{DSS} 68 V V_{GS(th)_Typ} 3.0 V I_D(@V_{GS}=10V) 80 A R_{DS(ON)_Typ}(@V_{GS}=10V) 7.3 mΩ

Product Summary





Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMTK70N07A	JMTK70N07A	3	Tape&Reel	TO-252-3L	2500	25000

Absolute Maximum Ratings (@ T_c = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit
V _{DS}	Drain-to-Source Voltage	Drain-to-Source Voltage		V
V _{GS}	Gate-to-Source Voltage		±20	V
	Continuous Drain Current	$T_{\rm C} = 25^{\circ}{\rm C}$	80	Α
Ъ	Continuous Drain Current	T _C = 100°C	51	A
I _{DM}	Pulsed Drain Current ⁽¹⁾	Pulsed Drain Current ⁽¹⁾		А
E _{AS}	Single Pulsed Avalanche Energy ⁽²⁾		227	mJ
P _D	Dower Dissipation	T _C = 25°C	46	W
' D	Power Dissipation	$T_{\rm C} = 100^{\circ}{\rm C}$	19	vv
T _J , T _{STG}	Junction & Storage Temperature Ra	Junction & Storage Temperature Range		°C

Thermal Characteristics

Symbol	Parameter	Мах	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	39	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.7	0/00

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
	racteristics					•
V _{(BR)DSS}	Drain-Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	68	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 68V, V_{GS} = 0V$	-	-	1.0	μA
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
	racteristics			<u> </u>	I	I
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.1	3.0	4	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	V _{GS} = 10V, I _D = 30A	-	7.3	8.6	mΩ
Dynami	c Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	1.0	-	Ω
C _{iss}	Input Capacitance		3111	4355	5879	pF
C_{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 34V,$ f = 1MHz	149	208	281	pF
C _{rss}	Reverse Transfer Capacitance	1 - 110112	109	152	206	pF
Qg	Total Gate Charge		50	70	95	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 34V, I_D = 30A$	17	24	33	nC
Q_{gd}	Gate Drain("Miller") Charge	$v_{\rm DS} = 34 v, v_{\rm D} = 30 A$	12	17	23	nC
Switchi	ng Characteristics					
t _{d(on)}	Turn-On DelayTime		-	19	-	ns
t _r	Turn-On Rise Time	V _{GS} = 10V, V _{DD} = 34V	-	27	-	ns
t _{d(off)}	Turn-Off DelayTime	$I_D = 30A, R_{GEN} = 3\Omega$	-	37	-	ns
t _f	Turn-Off Fall Time		-	10	-	ns
Body D	iode Characteristics			•	1	A
Is Maximum Continuous Body Diode Forward Current			-	-	80	А
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	320	А
$\rm V_{SD}$	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 30A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	L = 204 di/dt = 1004/wa	22	31	42	ns
Qrr	Body Diode Reverse Recovery Charge	I _F = 30A, di/dt = 100A/us	-	46	-	nC

Electrical Characteristics ($T_J = 25^{\circ}C$ unless otherwise specified)

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

 $2. \; E_{AS} \; \text{condition: Starting } T_J = 25C, \; V_{DD} = 34V, \; V_G = 10V, \; R_G = 250 \text{hm}, \; L = 0.5 \text{mH}, \; I_{AS} = 24.78\text{A}, \; V_{DD} = 0V \; \text{during time in avalanche}.$

3. $R_{\theta JA}$ is measured with the device mounted on a 1inch 2 pad of 2oz copper FR4 PCB.

4. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 0.5%.

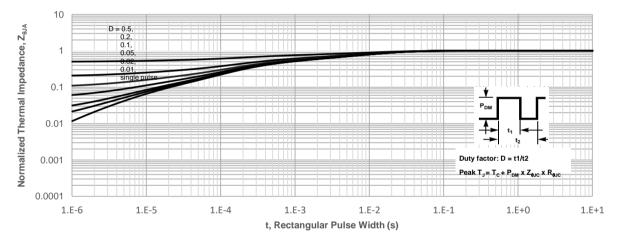


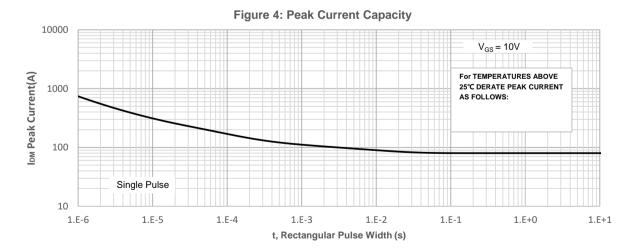


Typical Performance Characteristics

Figure 1: Power De-rating Figure 2: Current De-rating 1.2 $V_{GS} = 10V$ P_D(W) Multiplier 9.0 9.0 8.0 ID(A) 0.2 T_c(°C) Case Temperature T_c(°C) Case Temperature







м



Typical Performance Characteristics

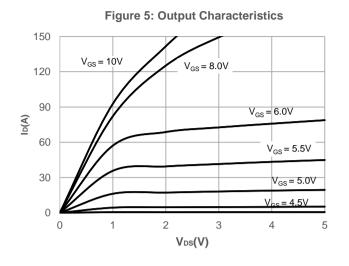
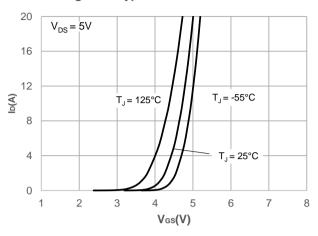


Figure 6: Typical Transfer Characteristics





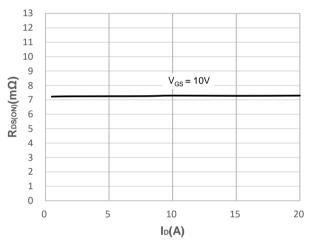
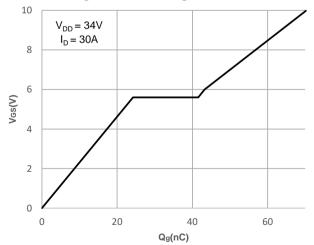
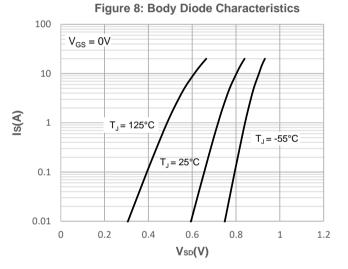
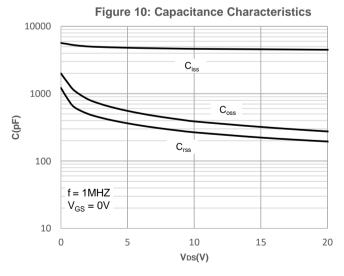


Figure 9: Gate Charge Characteristics









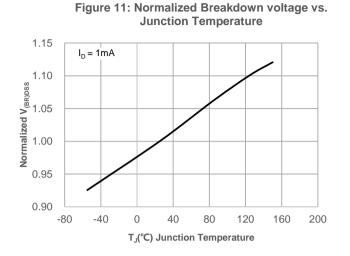
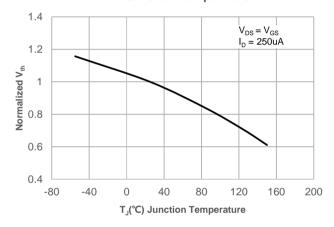
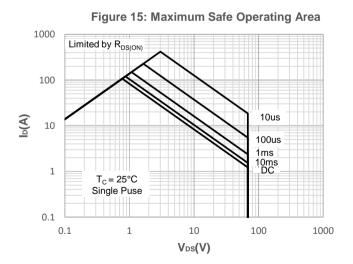
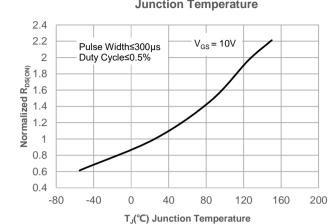


Figure 13: Normalized Threshold Voltage vs. Junction Temperature







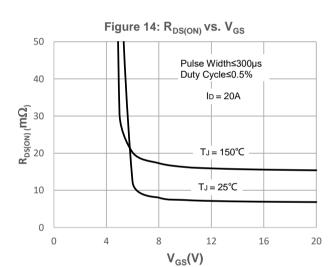


Figure 12: Normalized on Resistance vs. Junction Temperature

Test Circuit

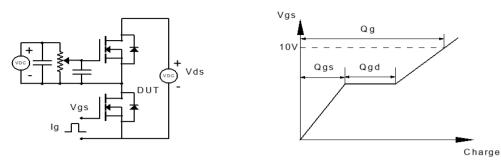


Figure 1: Gate Charge Test Circuit & Waveform

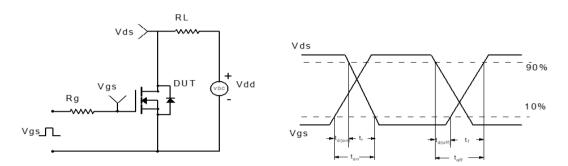


Figure 2: Resistive Switching Test Circuit & Waveform

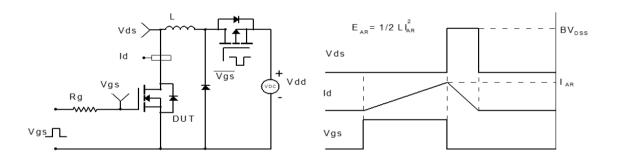


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

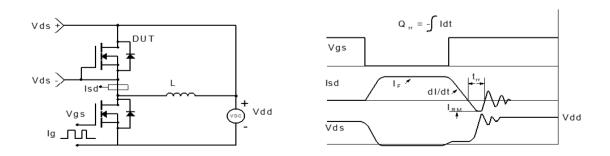
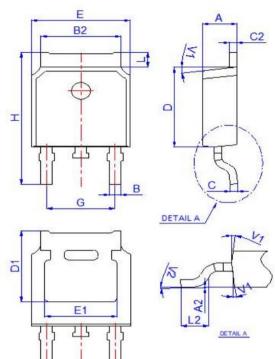


Figure 4: Diode Recovery Test Circuit & Waveform

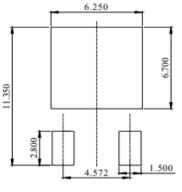


Package Mechanical Data(TO-252-3L)



Ref.	Dimensions						
	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Typ.	Max.	
A	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1	5.30REF			C	209RE	F	
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
Н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°	2	6°	

Recommended Soldering Footprint



DIMENSIONS:MILLIMETERS

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